

SE10080GK

N-Channel Enhancement-Mode MOSFET

Revision: A

General Description

Thigh Density Cell Design For Ultra Low On-Resistance Fully Characterized Avalanche Voltage and Current Improved Shoot-Through FOM

- Simple Drive Requirement
- Small Package Outline
- Surface Mount Device

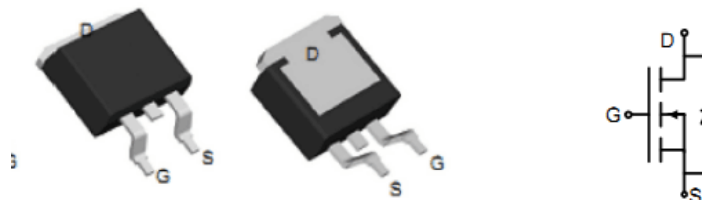
Features

For a single MOSFET

- $V_{DS} = 100V$
- $R_{DS(ON)} = 7.2m\Omega @ V_{GS}=10V$

Pin configurations

See Diagram below



Absolute Maximum Ratings

Parameter		Symbol	Rating	Units
Drain-Source Voltage		V_{DS}	100	V
Gate-Source Voltage		V_{GS}	± 20	V
Drain Current	Continuous	I_D	70	A
	Pulsed		280	
Avalanche Current		I_{AS}	46	A
Avalanche Energy L=0.1mH		E_{AS}	105	mJ
Total Power Dissipation	@TA=25°C	P_D	100	W
Operating Junction Temperature Range		T_J	-55 to 175	°C

SE10080GK

Electrical Characteristics (T _J =25°C unless otherwise noted)						
Symbol	Parameter	Test Conditions	Min	Typ	Max	Units
OFF CHARACTERISTICS (Note 2)						
BV _{DSS}	Drain-Source Breakdown Voltage	I _D =250μA, V _{GS} =0 V	100	115		V
I _{DSS}	Drain to Source Leakage Current	V _{DS} =100V, V _{GS} =0V			1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =20V			100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} = V _{GS} , I _D =250μA	2.2	3.0	3.8	V
R _{DS(ON)}	Static Drain-Source On-Resistance	V _{GS} =10V, I _D =35A	-	7.2	9.0	mΩ
		V _{GS} =6V, I _D =18A	-	8.5	11.0	mΩ
g _{FS}	Forward Transconductance	V _{DS} =5V, I _D =35A		90		S
R _g	Gate Resistance	V _{GS} =0V, V _{DS} =0V, f=1MHz		1.4	2.1	Ω
DYNAMIC PARAMETERS						
C _{iss}	Input Capacitance	V _{GS} =0V, V _{DS} =50V, f=1MHz		4550		pF
C _{oss}	Output Capacitance			360		pF
C _{rss}	Reverse Transfer Capacitance			230		pF
SWITCHING PARAMETERS						
Q _g	Total Gate Charge ²	V _{GS} =10V, V _{DS} =50V, I _D =35A		92		nC
Q _{gs}	Gate Source Charge			20		nC
Q _{gd}	Gate Drain Charge			36		nC
t _{d(on)}	Turn-On Delay Time	V _{GS} =10V, V _{DS} =50V, R _{GEN} =1.6Ω I _D =35A		20		ns
t _{d(off)}	Turn-Off Delay Time			50		ns
t _{d(r)}	Turn-On Rise Time			45		ns
t _{d(f)}	Turn-Off Fall Time			37		ns
Thermal Resistance						
Symbol	Parameter	Typ	Max	Units		
R _{θJC}	Thermal Resistance Junction to Case(t≤10s)	-	1.5	°C/W		

Typical Characteristics

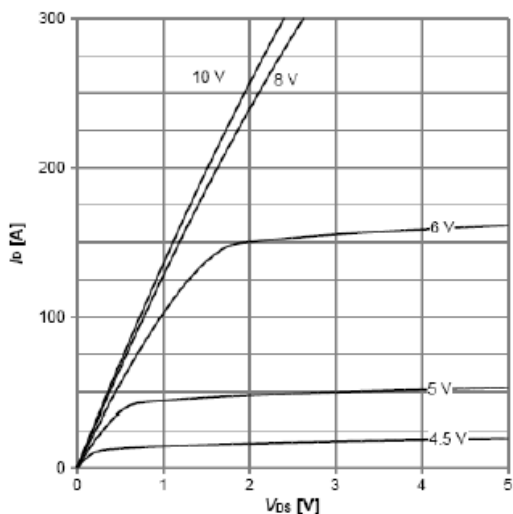


Figure 1: On-Region Characteristics

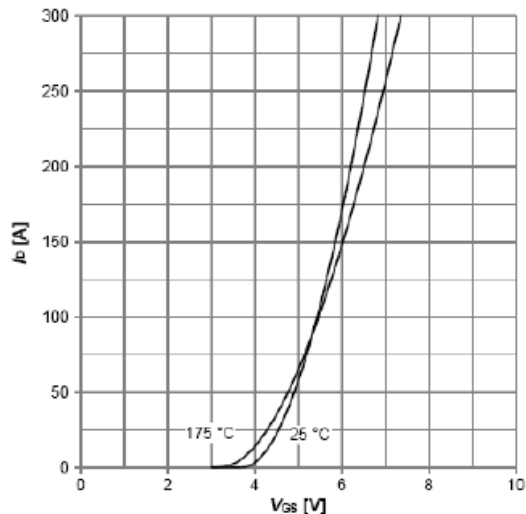


Figure 2: Transfer Characteristics

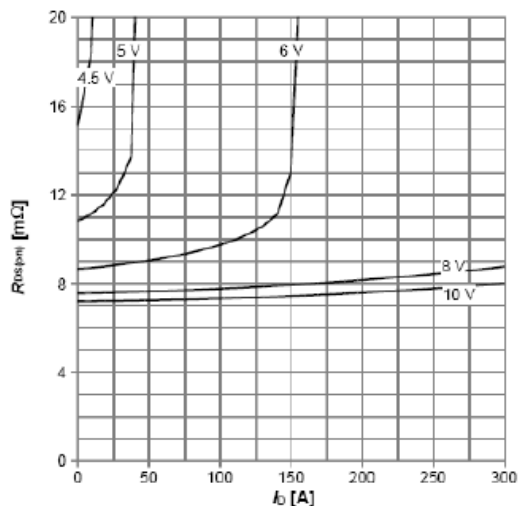


Figure 3: On-Resistance vs Drain current and Gate voltage

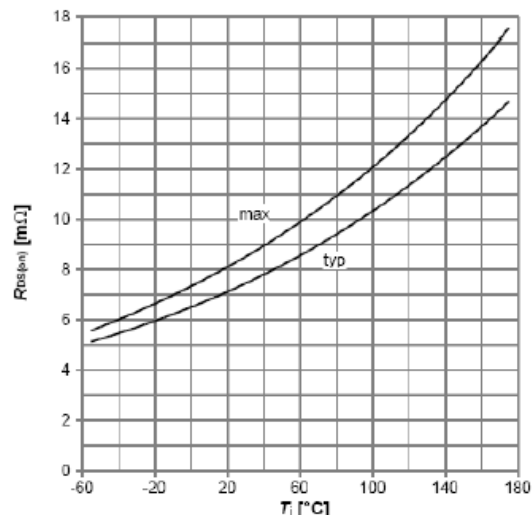


Figure 4: On-Resistance vs Junction Temperature

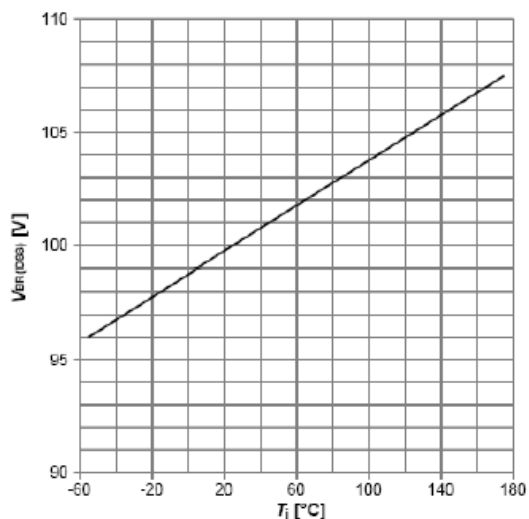


Figure 5: Drain-Source breakdown voltage

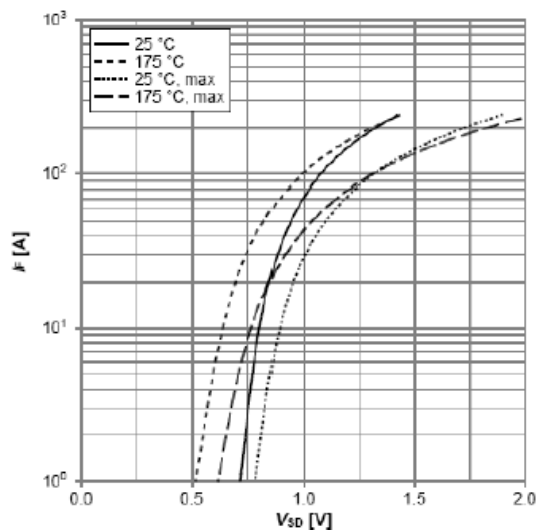


Figure 6: Body-Diode Characteristics

Typical Characteristics

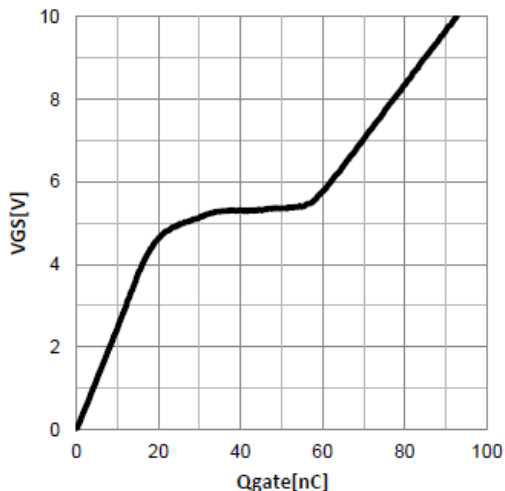


Figure 7: Gate-Charge Characteristics

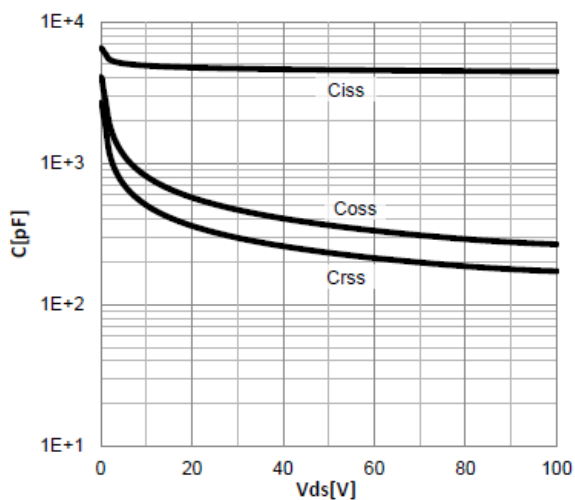


Figure 8: Capacitance Characteristics

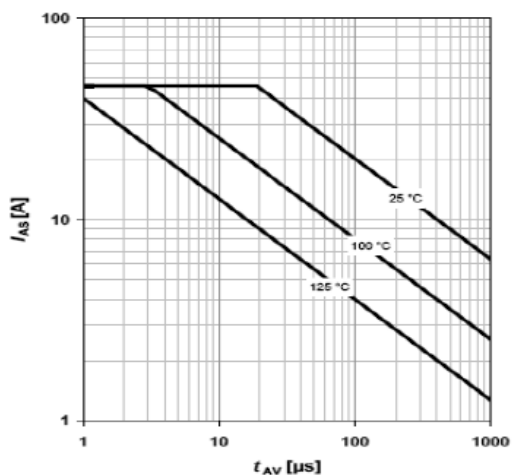


Figure 9: Avalanche Characteristics

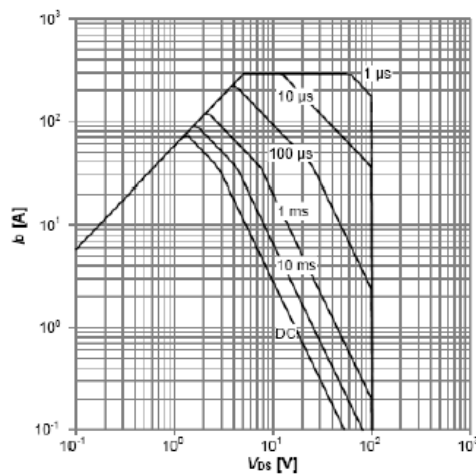


Figure 10: Maximum Forward Biased Safe Operating Area

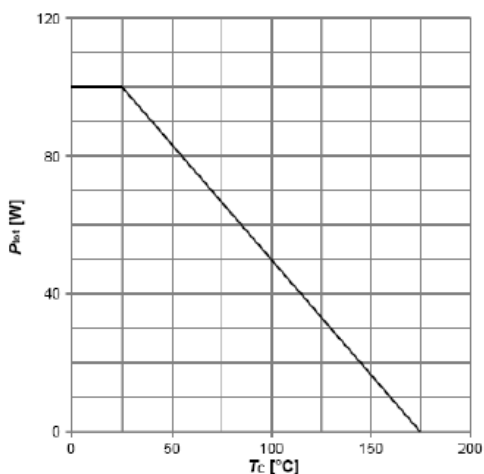


Figure 11: Power dissipation

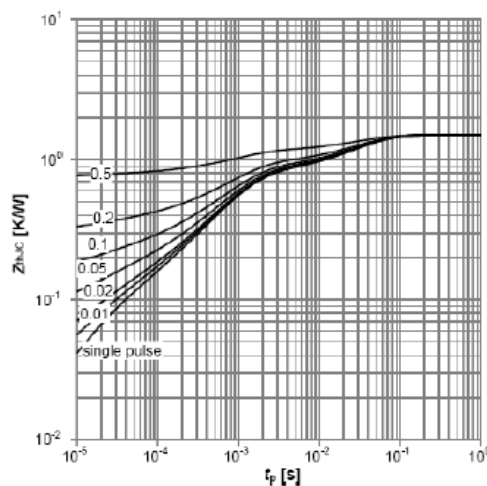
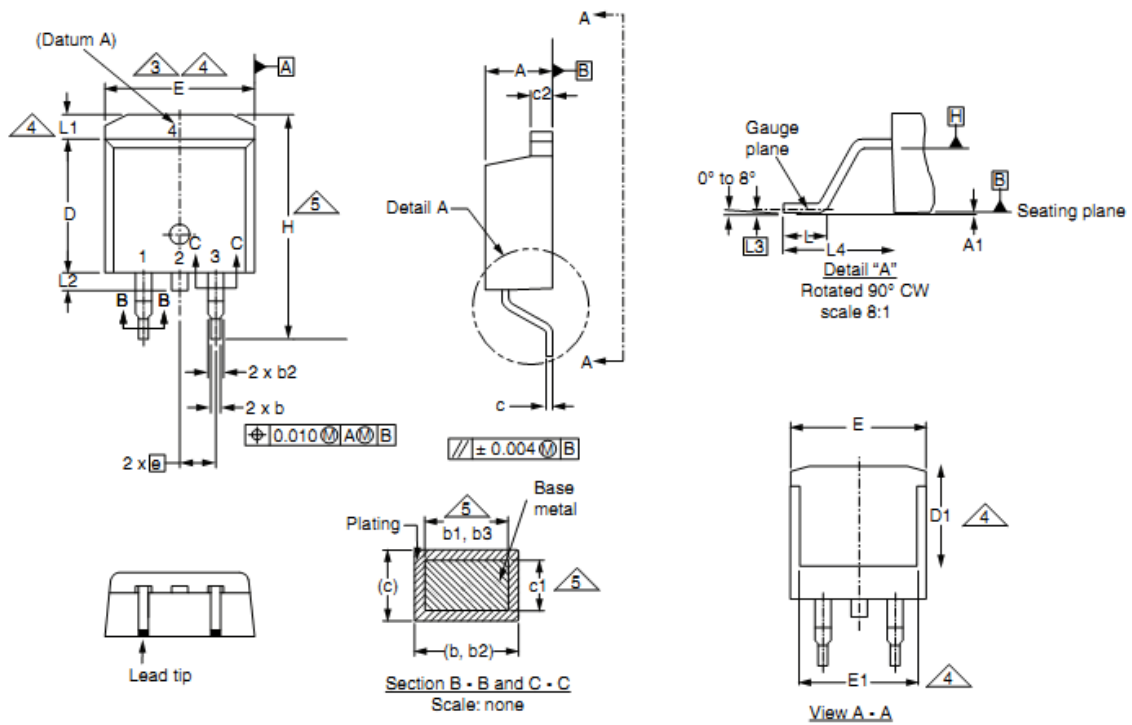


Figure 12: Maximum Transient Thermal Impedance

SE10080GK

Package Outline Dimension

TO-263



DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
A	4.06	4.83	0.160	0.190
A1	0.00	0.25	0.000	0.010
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
c	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065
D	8.38	9.65	0.330	0.380

DIM.	MILLIMETERS		INCHES	
	MIN.	MAX.	MIN.	MAX.
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
e	2.54 BSC		0.100 BSC	
H	14.61	15.88	0.575	0.625
L	1.78	2.79	0.070	0.110
L1	-	1.65	-	0.066
L2	-	1.78	-	0.070
L3	0.25 BSC		0.010 BSC	
L4	4.78	5.28	0.188	0.208

**The SINO-IC logo is a registered trademark of ShangHai Sino-IC Microelectronics Co., Ltd.
© 2005 SINO-IC – Printed in China – All rights reserved.**

SHANGHAI SINO-IC MICROELECTRONICS CO., LTD

Add: Building 3, Room 3401-03, No.200 Zhangheng Road, ZhangJiang Hi-Tech Park, Pudong,
Shanghai 201203, China

Phone: +86-21-33932402 33932403 33932405 33933508 33933608

Fax: +86-21-33932401

Email: webmaster@sino-ic.net

Website: <http://www.sino-ic.net>